## Notice of References Cited Application/Control No. 10/043,047 Examiner Art Unit Page 1 of 1 Tse Chen Applicant(s)/Patent Under Reexamination YOO ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,510,503	01-2003	Gillingham et al.	711/167
	В	US-6,029,250	02-2000	Keeth, Brent	713/400
	С	US-5,432,823	07-1995	Gasbarro et al.	375/356
	D	US-6,326,853	12-2001	Moyal et al.	· 331/34
	Е	US-5,379,248	01-1995	Wada et al.	365/63
	F	US-6,043,704	03-2000	Yoshitake, Akihiro	327/565 .
	G	US-5,998,860	12-1999	Chan et al.	257/679
	Н	US-6,397,312	05-2002	Nakano et al.	711/167
	_	US-5,390,356	02-1995	Houlberg, Christian L.	703/23
	J	US-			
	К	US			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Ρ					
	a				•	
	R					
	s					
	Ţ					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	w		*					
	х							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.